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AN INTERFACE DEVICE

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The invention relates to an interface device for providing an interface between testing equipment and an integrated circuit to be tested using the testing equipment.

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A probe card is used in semiconductor wafer fabrication and/or packaging facilities to test the integrity of every semiconductor chip (or die) produced. The process of testing involves testing equipment referred to as "probers" and an interface device that couples the testing equipment to the die to be tested. The interface device is commonly known as a "probe card". The probe card generally comprises a large number of probes, which take the form of pins. The pins are arranged on a printed circuit board, or other supporting structure, in a pattern that corresponds to the layout of the bonding pads on the die to be tested. Each die requires a probe card with a pin pattern that is specific to the layout of the bond pads on the die.

Test signals are exchanged between the prober and the die via the probe card and in particular, the pins that contact the bond pads on the die to be tested. The quality of signals received by the prober from the die is dependent on the quality of the probe card and the quality of contact between the pins and the bond pads on the die.

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Conventional probe cards comprise a number of cantilevered probes fixed by epoxy resin to a ceramic or aluminium retaining ring. Typically, the free end of each cantilevered probe (ie the tip which contacts the bond pad) is overhanging the retaining ring by approximately 5mm to 6mm and there is an average pitch (ie spacing between the tips) of between 80 μ m to 200 μ m.

However, as chip geometries and resulting bond pad pitches are getting smaller and smaller (currently about 50 μ m) it is becoming increasingly difficult to design and build probecards using conventional cantilever pin designs.

Therefore, in order to achieve smaller probe pitches, smaller diameter wire is being used to manufacture the probes. However, using thinner wire has the disadvantage that the probes are substantially weaker and the overhanging cantilevered design of the probes makes them susceptible to lateral deflections at the tip. Therefore, the tips can not reliably maintain the correct x-y position. This has the risk that the tip may not contact the correct bond pad on the die during testing, resulting in the prober possibly giving an incorrect test result.

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In accordance with a first aspect of the present invention, an interface device for providing an interface between

testing equipment and an integrated circuit to be tested comprises a body member; a number of elongate contact members, each elongate contact member comprising a contact end, adapted to contact a bond pad of an integrated circuit to be tested, and a body portion coupled to the body member; and a guide member mounted on the body member, the guide member comprising a substantially planar member having a number of apertures therein, the contact end of each elongate member extending through a respective aperture in the guide member, and the width of each contact end being less than the width of the respective aperture to permit lateral movement of each contact end within the respective aperture.

An advantage of the invention is that, as the contact end of each elongate member extends through a respective aperture in the guide member, the guide member limits lateral displacement of the contact ends.

Preferably, the planar member is manufactured from a glass material, such as borosilicate glass.

In accordance with a second aspect of the present invention, an elongate member for an interface device for providing an interface between testing equipment and an integrated circuit to be tested comprises a body portion

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Preferably, the interface device further comprises a printed circuit board to which the ends of the contact members opposite to the contact ends are coupled and the printed circuit board is adapted to permit the testing equipment to be coupled to the printed circuit board.

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Preferably, the elongate contact member may be formed from metal wire with a diameter of 1 mil to 10 mil (25 μ m to 250 μ m) and is preferably in the region of 2 mil to 10 mil (50 μ m to 250 μ m). Typically, the contact surface of the contact ends may have a diameter of approximately 0.5 mil to 5 mils (12.5 μ m to 125 μ m) and preferable 1 mil to 2.5 mils (25 μ m to 62.5 μ m). The contact surface may be either planar or curved. Preferably, the contact members may be tungsten, beryllium copper, palladium, paliney or an alloy of two or more of these materials.

In accordance with a third aspect of the invention, a method of forming a through bore in a piece of material comprises generating a substantially parallel beam of coherent light, illuminating an object having a substantially circular cross section with a diameter less than the diameter of the beam with the substantially parallel beam to form an annular beam, and focusing the annular beam onto the piece of material so that the annular beam incident on the piece of material has an external diameter corresponding to that of the desired through bore to burn away a corresponding annular piece of material to form the through bore.

Preferably, the coherent light is generated by a laser, which may be an excimer laser. Typically, the light

generated by the excimer laser has a wavelength of approximately 193nm.

Typically, the object having the circular cross section may be a spherical object, such as a steel ball. Preferably, the object reflects the light incident on it to minimise heating of the object.

Typically, the through bore to be formed in the piece of material has a diameter less than 100 μ m and may be from 10 μ m to 100 μ m.

Preferably, the apertures in the guide member in the first aspect of the invention are formed using the method in accordance with the third aspect of the invention.

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An example of an interface device in accordance with the invention will now be described with reference to the accompanying drawings, in which:

Figure 1 is a schematic perspective view of a section of an interface device including a guide member;

Figure 2 is a side view of a portion of the interface device; and

Figure 3 is a schematic view of apparatus for forming apertures in the guide member forming part of the

interface device shown in Figures 1 and 2.

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Figure 1 shows a schematic view of a portion of a probe card 2. The probe card 2 includes a ring 1 formed from ceramic, aluminium or titanium, a guide member in the form of a glass wafer 3 and a number of contact pins 5 mounted on the ring 1 by means of a ceramic shim 6 and epoxy resin 7.

As shown in more detail in Figure 2, each of the contact pins 5 comprises a central body portion 10 which rests on and is fixed to the ceramic shim 6, a contact end 13 and a PCB end 12 which is electrically coupled by solder 20 to a trace 22 on a printed circuit board (PCB) 21.

The contact pins 5 are typically manufactured from a metal wire such as tungsten, beryllium copper, palladium, paliney alloy or any other suitable metal material. The contact pins 5 can also be comprised of a suitable base metal with another metal coated on this base metal. The wire diameter is typically in the region of 1 mil to 10 mil (25µm to 250µm) and the surface of the contact end 13 may have a diameter of approximately 1 mil to 2.5 mil (25µm to 62.5µm) with a flat or curved surface. In addition, the contact end 13 is etched to form a taper.

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Preferably, the laser drilling is performed using an optical arrangement as shown in Figure 3. An excimer laser 30 emits light with a wavelength of 193nm and an energy of 200mJ per pulse. The light beam from the laser is then collimated by collimating optics 31 to form a collimated beam of light with a circular cross-section. A steel ball 32 is fixed to a glass plate 33. The steel ball 32 has a diameter which is less than that of the output beam from the collimating optics. Therefore, when the centre of the collimated beam strikes the center of the steel ball, the central portion of the collimated beam is reflected and scattered from the steel ball but the outermost section of

In addition, as the axis of the apertures 16 is substantially vertical, vertical movement of the contact ends 13 is not affected by the presence of the glass wafer 3.